

## Dual P-Channel Enhancement Mode Field Effect Transistor

### General Description

The AON2801 uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 1.8V. This device is suitable for use as a load switch or in PWM applications.

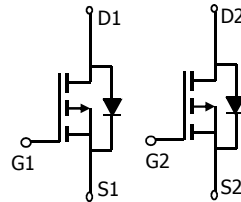
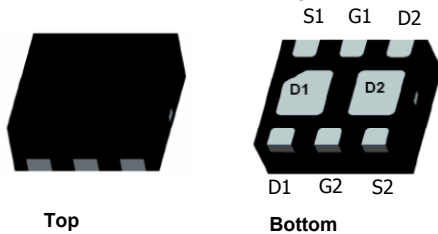
RoHS and Halogen-Free Compliant

### Features

$V_{DS} (V) = -20V$   
 $I_D = -3A$  ( $V_{GS} = -4.5V$ )  
 $R_{DS(ON)} < 120m\Omega$  ( $V_{GS} = -4.5V$ )  
 $R_{DS(ON)} < 160m\Omega$  ( $V_{GS} = -2.5V$ )  
 $R_{DS(ON)} < 200m\Omega$  ( $V_{GS} = -1.8V$ )



DFN 2x2 Package



Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	-20	V
Gate-Source Voltage	$V_{GS}$	$\pm 8$	V
Continuous Drain Current <sup>A</sup>	$I_D$	$T_A = 25^\circ C$	-3
		$T_A = 70^\circ C$	-2.3
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	-15	A
Power Dissipation <sup>A</sup>	$P_{DSM}$	$T_A = 25^\circ C$	1.5
		$T_A = 70^\circ C$	0.95
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	$^\circ C$

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	35	45	$^\circ C/W$
Maximum Junction-to-Ambient <sup>A</sup>		Steady-State	65	85
Maximum Junction-to-Ambient <sup>B</sup>	$R_{\theta JA}$	120	155	$^\circ C/W$
Maximum Junction-to-Ambient <sup>B</sup>		Steady-State	175	235

**Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	I <sub>D</sub> =-250μA, V <sub>GS</sub> =0V	-20			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =-20V, V <sub>GS</sub> =0V T <sub>J</sub> =55°C			-1 -5	μA
I <sub>GSS</sub>	Gate-Body leakage current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±8V			±100	nA
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> I <sub>D</sub> =-250μA	-0.3	-0.55	-1	V
I <sub>D(ON)</sub>	On state drain current	V <sub>GS</sub> =-4.5V, V <sub>DS</sub> =-5V	-15			A
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-3A T <sub>J</sub> =125°C		100 135	120 170	mΩ
		V <sub>GS</sub> =-2.5V, I <sub>D</sub> =-2.6A		128	160	mΩ
		V <sub>GS</sub> =-1.8V, I <sub>D</sub> =-1.5A		160	200	mΩ
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> =-5V, I <sub>D</sub> =-3A		6		S
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> =-1A, V <sub>GS</sub> =0V		-0.76		V
I <sub>S</sub>	Maximum Body-Diode Continuous Current				-1	A
<b>DYNAMIC PARAMETERS</b>						
C <sub>ISS</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =-10V, f=1MHz		540	700	pF
C <sub>OSS</sub>	Output Capacitance			90		pF
C <sub>RSS</sub>	Reverse Transfer Capacitance			63		pF
R <sub>g</sub>	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz		9.5		Ω
<b>SWITCHING PARAMETERS</b>						
Q <sub>g</sub>	Total Gate Charge	V <sub>GS</sub> =-4.5V, V <sub>DS</sub> =-10V, I <sub>D</sub> =-3A		5	6.5	nC
Q <sub>gs</sub>	Gate Source Charge			1.2		nC
Q <sub>gd</sub>	Gate Drain Charge			1		nC
t <sub>D(on)</sub>	Turn-On Delay Time	V <sub>GS</sub> =-4.5V, V <sub>DS</sub> =-10V, R <sub>L</sub> =1.5Ω, R <sub>GEN</sub> =3Ω		5		ns
t <sub>r</sub>	Turn-On Rise Time			40		ns
t <sub>D(off)</sub>	Turn-Off Delay Time			28.5		ns
t <sub>f</sub>	Turn-Off Fall Time			46		ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time		I <sub>F</sub> =-3A, dI/dt=100A/μs		21	28
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	I <sub>F</sub> =-3A, dI/dt=100A/μs		9.1		nC

A: The value of R<sub>θJA</sub> is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25° C. The Power dissipation P<sub>DSM</sub> is based on R<sub>θJA</sub> and the maximum allowed junction temperature of 150° C. The value in any given application depends on the user's specific board design, and the maximum temperature of 150° C may be used if the PCB allows it to.

B: The value of R<sub>θJA</sub> is measured with the device mounted on a minimum pad board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25° C. The Power dissipation P<sub>DSM</sub> is based on R<sub>θJA</sub> and the maximum allowed junction temperature of 150° C. The value in any given application depends on the user's specific board design, and the maximum temperature of 150° C may be used if the PCB allows it to.

C: The R<sub>θJA</sub> is the sum of the thermal impedance from junction to case R<sub>θJC</sub> and case to ambient.

D: The static characteristics in Figures 1 to 6 are obtained using <300 μs pulses, duty cycle 0.5% max.

E: These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25° C. The SOA curve provides a single pulse rating.

\*This device is guaranteed green after data code 7111 (Oct 15 2007).

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

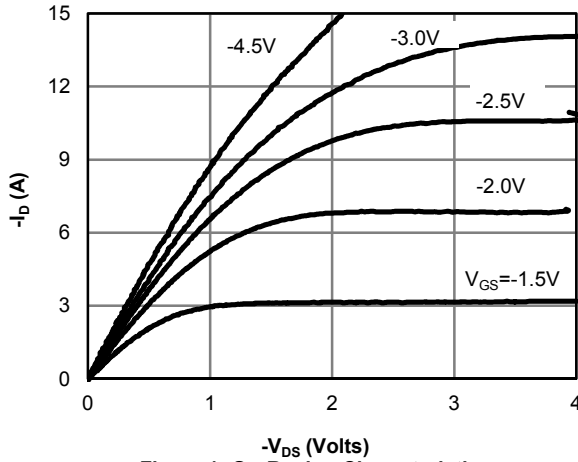


Figure 1: On-Region Characteristics

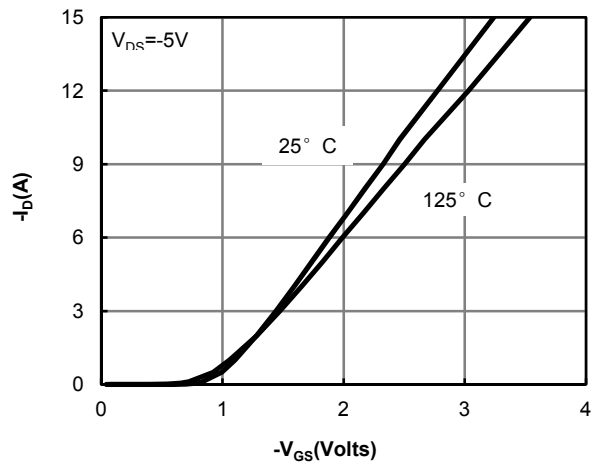


Figure 2: Transfer Characteristics

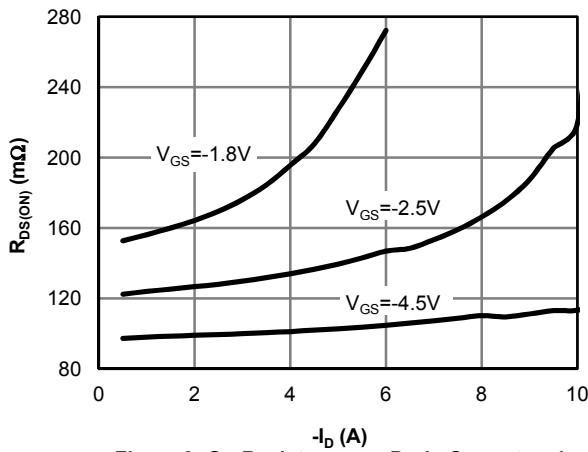


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

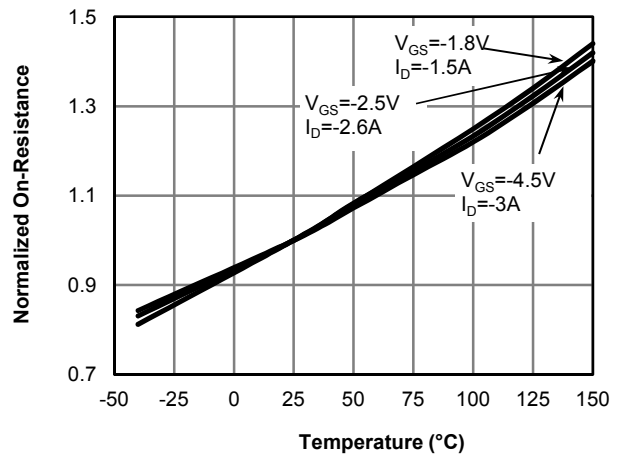


Figure 4: On-Resistance vs. Junction Temperature (Note E)

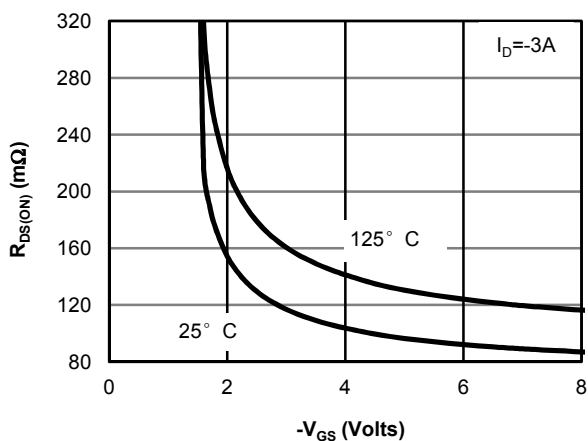


Figure 5: On-Resistance vs. Gate-Source Voltage

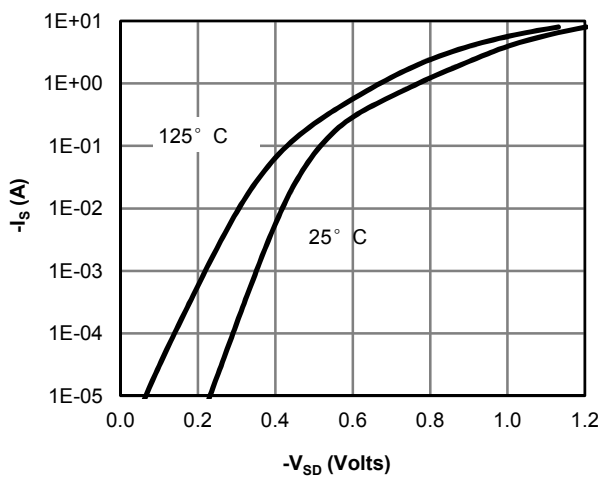
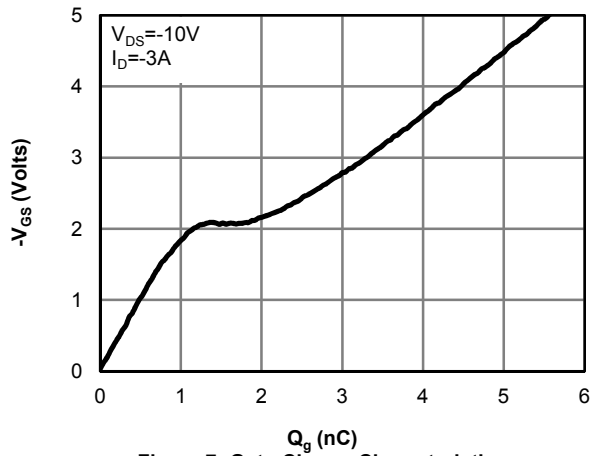
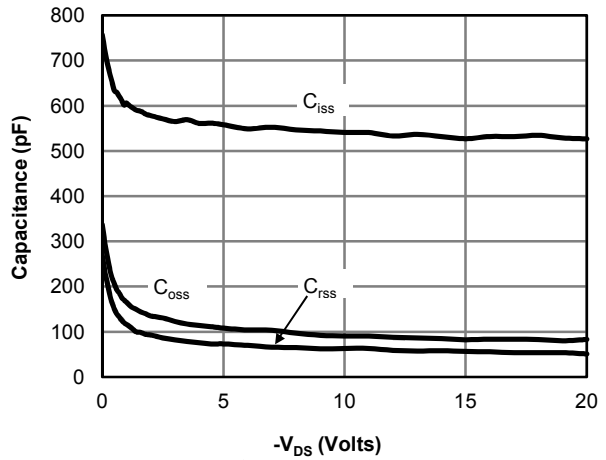


Figure 6: Body-Diode Characteristics

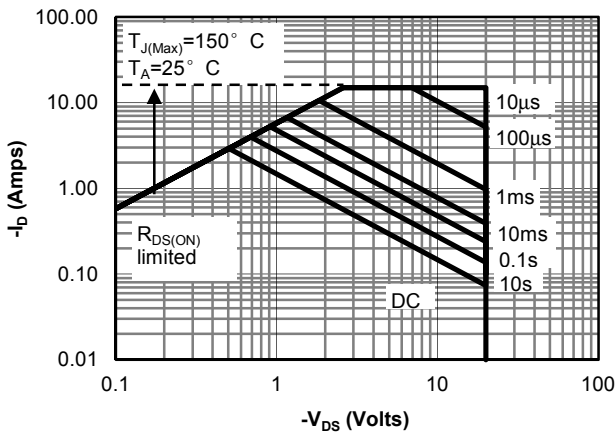
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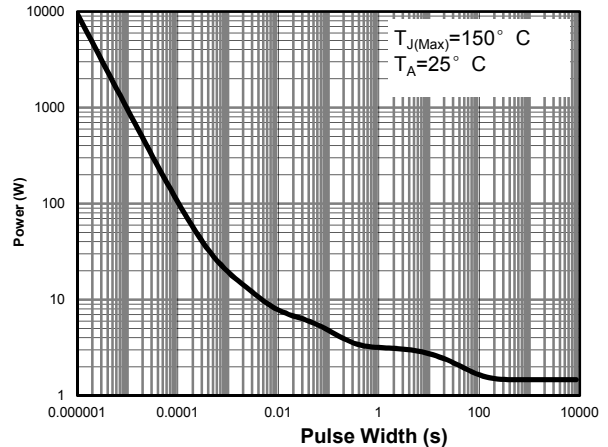
**Figure 7: Gate-Charge Characteristics**



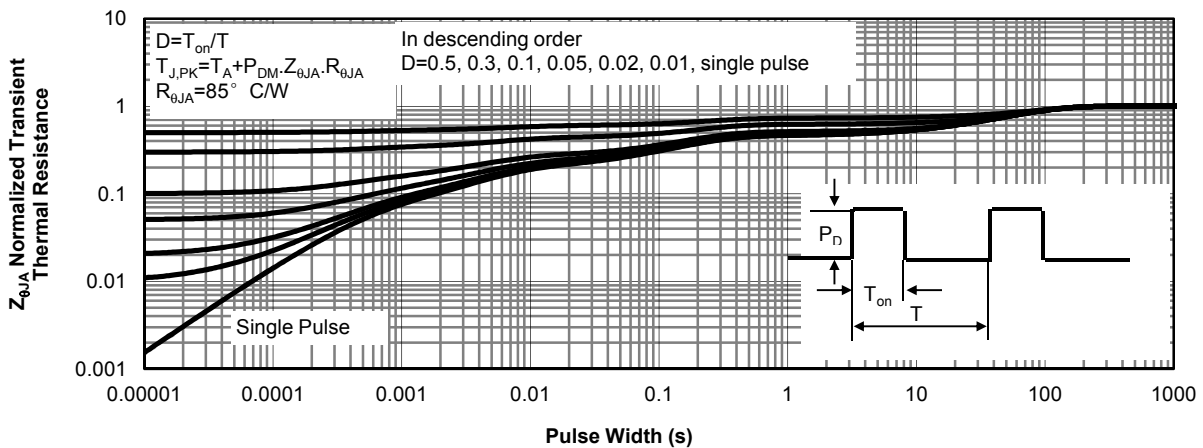
**Figure 8: Capacitance Characteristics**



**Figure 9: Maximum Forward Biased Safe Operating Area (Note E)**

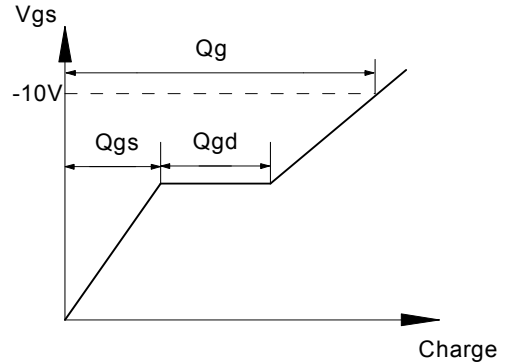
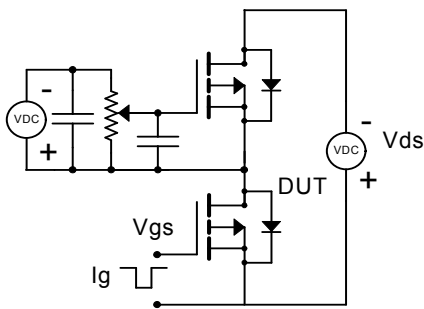


**Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)**

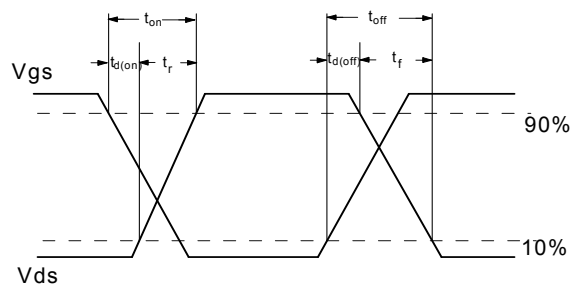
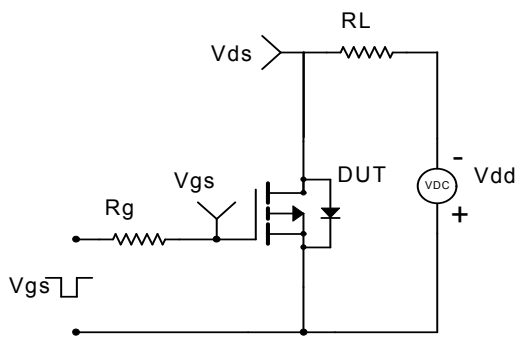


**Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)**

Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

